


<b>Search Notes</b> 	<b>Application/Control No.</b> 10038169	<b>Applicant(s)/Patent Under Reexamination</b> BONEH ET AL.
	<b>Examiner</b> Baotran N To	<b>Art Unit</b> 2435

SEARCHED			
Class	Subclass	Date	Examiner
713	165 and 189	11/19/2009	BT
726	2	11/19/2009	BT
705	51	11/19/2009	BT
709	223	11/19/2009	BT

SEARCH NOTES		
Search Notes	Date	Examiner
EAST SEARCH (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB)	11/19/2009	BT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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